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| Notice of References Cited | Application/Control No. 10/816,170 | Applicant(s)/Patent Under Reexamination MULDER ET AL. | |
| | Examiner Kevin Gutierrez | Art Unit 2851 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-2003/0151730 A1 | 08-2003 | Shinoda, Kenichiro | 355/69 |
| * | B | US-5,859,707 A | 01-1999 | Nakagawa et al. | 356/401 |
| * | C | US-5,121,160 A | 06-1992 | Sano et al. | 355/53 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
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